

**Search Notes**

Application/Control No.

10/630,742

Examiner

Sikyin Ip

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner
420	503		
148	431	12/8/2005	SI

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
STN	12/8/2005	SI
eDAN inventor names searched	12/11/2005	SI